

BS ISO 16531:2013



BSI Standards Publication

**Surface chemical analysis —
Depth profiling — Methods for
ion beam alignment and the
associated measurement of
current or current density for
depth profiling in AES and XPS**

National foreword

This British Standard is the UK implementation of ISO 16531:2013.

The UK participation in its preparation was entrusted to Technical Committee CII/60, Surface chemical analysis.

A list of organizations represented on this committee can be obtained on request to its secretary.

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